

<b>PCN Number:</b>	20160526000	<b>PCN Date:</b>	05/29/2016
<b>Title:</b>	Qualification of RFAB for Select LBC8 Devices		
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Dept:</b>	Quality Services
<b>Proposed 1<sup>st</sup> Ship Date:</b>	08/29/2016	<b>Estimated Sample Availability:</b>	Date provided at sample request.
<b>Change Type:</b>			
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials
		<input type="checkbox"/>	Part number change
<input type="checkbox"/>		<input type="checkbox"/>	Assembly Materials
		<input type="checkbox"/>	Mechanical Specification
		<input type="checkbox"/>	Test Process
		<input type="checkbox"/>	Wafer Bump Process
		<input type="checkbox"/>	Wafer Fab Process

**PCN Details**

**Description of Change:**

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional wafer FAB source for the selected devices listed in "Product Affected" section.

Current Sites			Additional Sites		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
DP1DM5	LBC8	200 mm	RFAB	LBC8	300 mm

Qual details are provided in the Qual Data Section.

**Reason for Change:**

Continuity of Supply

**Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):**

None

**Changes to product identification resulting from this PCN:**

**Current**

Chip Sites	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	DM5	USA	Dallas

**New**

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
<b>RFAB</b>	<b>RFB</b>	<b>USA</b>	<b>Richardson</b>

Sample product shipping label (not actual product label)

 MADE IN: Malaysia 2DC: 20 MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 <b>LBL: 5A (L)T0:1750</b>		(1P) SN74LS07NSR	(D) 0336
		(Q) 2000	(31T) LOT: 3959047MLA
		(4W) TKY (1T) 7523483S12	(P)
		(2P) REV: (1) 0033317	(21L) CCO:USA
		(20L) CSO: SHE	(23L) ACO: MYS

<b>Product Affected:</b>				
DRV10975PWP	DRV10975ZPWPR	DRV10983ZPWP	PDRV10975PWPR	
DRV10975PWPR	DRV10983PWP	DRV10983ZPWPR	PDRV10975ZPWP	
DRV10975ZPWP	DRV10983PWPR	PDRV10975PWP	PDRV10983ZPWP	

### **QUALIFICATION DATA**

**DRV10983PWPR add RFAB as second wafer fab  
Approve Date 02-May-2016**

<b>Attributes</b>	<b>Qual Device: DRV10983</b>	<b>QBS Product Reference: DRV10983</b>	<b>QBS Process Reference: SN96019PFP</b>
<b>Assembly Site</b>	TAI/TITL	TAI/TITL	PHI (TIPI)
<b>Package Family</b>	TSSOP	TSSOP	HTQFP
<b>Flammability Rating</b>	UL 94 V-0	UL 94 V-0	UL 94 V-0
<b>Wafer Fab Supplier</b>	RFAB	DMOS5	RFAB
<b>Wafer Process</b>	LBC8	LBC8	LBC8

- QBS: Qual By Similarity
- Qual Device DRV10983 is qualified at LEVEL2-260C

### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

<b>Type</b>	<b>Test Name / Condition</b>	<b>Duration</b>	<b>Qual Device: DRV10983</b>	<b>QBS Product Reference: DRV10983</b>	<b>QBS Process Reference: SN96019PFP</b>
AC	Autoclave 121C	96 Hours	-	-	3/231/0
CDM	ESD - CDM	1500 V	-	1/3/0	3/9/0
ED	Auto Electrical Distributions	Cpk>1.67 Room, hot, and cold test	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0
HBM	ESD - HBM	2500 V	-	1/3/0	-
HTOL	Life Test, 125C	1000 Hours	-	-	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0
HTSL	High Temp. Storage Bake, 175C	500 Hours	-	-	-
LU	Latch-up	(per JESD78)	-	2/12/0	1/6/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	1/77/0	3/231/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

**Green/Pb-free Status:**

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

<b>Location</b>	<b>E-Mail</b>
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>